


<b>Search Notes</b> 	<b>Application/Control No.</b> 10051726	<b>Applicant(s)/Patent Under Reexamination</b> UY ET AL.
	<b>Examiner</b> HAL I KAPLAN	<b>Art Unit</b> 2836

SEARCHED			
Class	Subclass	Date	Examiner
307	65	2/5/2009	HK
307	85	2/5/2009	HK
307	86	2/5/2009	HK
307	87	2/4/2009	HK
307	130	2/4/2009	HK
327	518	2/4/2009	HK
327	520	2/4/2009	HK

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	2/4/2009	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	2/5/2009	HK
307/64-66 (cursory)	2/5/2009	HK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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